

<b>Notice of References Cited</b>	Application/Control No. 10/585,121	Applicant(s)/Patent Under Reexamination MARUYAMA ET AL.	
	Examiner HENG M. CHAN	Art Unit 1728	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,188,768 A	02-1993	Sotomura, Tadashi	252/519.34
*	B	US-2005/0072462 A1	04-2005	Kang et al.	136/263
*	C	US-2005/0260786 A1	11-2005	Yoshikawa et al.	438/085
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	WO 2004017452 A1	02-2004	World Intellect	YOSHIKAWA et al.	H01M 14/00
	O					
	P					
	Q					
	R					
	S					
	I					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.